

RECLAIMING VIRGIN TEST WAFERS

Abstract of the Disclosure

A method and system for reclaiming virgin test wafers by polishing a very thin layer from the wafer surface, applying a low down force between the wafer and the pad, with a dilute, low basic slurry. By polishing only a few hundred Angstroms of silicon from the wafer surface, a virgin test wafer may be repeatedly reclaimed and reused for periodic defect monitoring.